

Application/Control No.	Applicant(s)/Patent under Reexamination
10/054,581	ROCKWELL ET AL.
Examiner	Art Unit
Christina V Loung	2633

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST search (see search history)	7/25/2005	Le		
IEEE database search (keywords included: "tunable laser")	7/25/2005	ce		
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